

**April 2010** 

## FDME510PZT

# P-Channel PowerTrench® MOSFET -20 V, -6 A, 37 m $\Omega$

#### **Features**

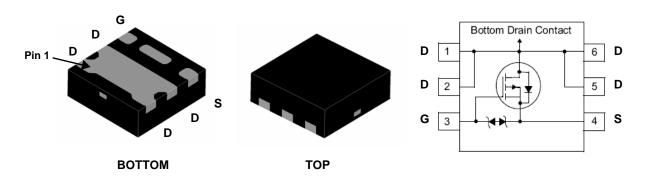
- Max  $r_{DS(on)}$  = 37 m $\Omega$  at  $V_{GS}$  = -4.5 V,  $I_D$  = -6 A
- Max  $r_{DS(on)} = 50 \text{ m}\Omega$  at  $V_{GS} = -2.5 \text{ V}$ ,  $I_D = -4 \text{ A}$
- Max  $r_{DS(on)} = 65 \text{ m}\Omega$  at  $V_{GS} = -1.8 \text{ V}$ ,  $I_D = -3 \text{ A}$
- $\blacksquare$  Max  $\rm r_{DS(on)}$  = 100 m $\Omega$  at  $\rm V_{GS}$  = -1.5 V,  $\rm I_D$  = -2 A
- Low profile: 0.55 mm maximum in the new package MicroFET 1.6x1.6 **Thin**
- Free from halogenated compounds and antimony oxides
- HBM ESD protection level > 2400V (Note3)
- RoHS Compliant



#### **General Description**

This device is designed specifically for battery charging or load switching in cellular handset and other ultraportable applications. It features a MOSFET with low on-state resistance.

The MicroFET 1.6x1.6 **Thin** package offers exceptional thermal performance for its physical size and is well suited to switching and linear mode applications.



MicroFET 1.6x1.6 Thin

## MOSFET Maximum Ratings T<sub>A</sub> = 25 °C unless otherwise noted

Symbol	Paramet		Ratings	Units	
V <sub>DS</sub>	Drain to Source Voltage			-20	V
$V_{GS}$	Gate to Source Voltage			±8	V
	Drain Current -Continuous	T <sub>A</sub> = 25 °C	(Note 1a)	-6	۸
<sup>I</sup> D	-Pulsed			-15	Α
C	Power Dissipation for Single Operation	T <sub>A</sub> = 25 °C	(Note 1a)	2.1	W
$P_{D}$	Power Dissipation for Single Operation	T <sub>A</sub> = 25 °C	(Note 1b)	0.7	VV
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperatu	ure Range		-55 to +150	°C

#### **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	60	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1b)	175	C/VV

### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
7T	FDME510PZT	MicroFET 1.6x1.6 Thin	7 "	8 mm	5000 units

# **Electrical Characteristics** $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$	-20			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D$ = -250 μA, referenced to 25 °C		-13		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -16 V, V <sub>GS</sub> = 0 V			-1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 8 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μΑ

#### On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = -250 \mu A$	-0.4	-0.5	-1.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = -250 $\mu$ A, referenced to 25 °C		3		mV/°C
	$V_{GS} = -4.5 \text{ V}, I_D = -6 \text{ A}$		31	37		
		$V_{GS} = -2.5 \text{ V}, I_D = -4 \text{ A}$		38	50	mΩ
rno( )	Drain to Source On Resistance	$V_{GS} = -1.8 \text{ V}, I_D = -3 \text{ A}$		48	65	
r <sub>DS(on)</sub>	Diam to course on resistance	$V_{GS} = -1.5 \text{ V}, I_D = -2 \text{ A}$		57	100	11152
		$V_{GS} = -4.5 \text{ V}, I_D = -5 \text{ A},$ $T_J = 125 ^{\circ}\text{C}$		40	60	
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = -5 \text{ V}, I_{D} = -6 \text{ A}$		21		S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 40.V.V 0.V	1120	1490	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1 \text{ MHz}$	155	210	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1 1/11/12	140	210	pF

## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		6.5	13	ns
t <sub>r</sub>	Rise Time	$V_{DD}$ = -10 V, $I_{D}$ = -6 A $V_{GS}$ = -4.5 V, $R_{GEN}$ = 6 $\Omega$	10	16	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = -4.5 \text{ V}, R_{GEN} = 0.22$	93	149	ns
t <sub>f</sub>	Fall Time		54	86	ns
$Q_g$	Total Gate Charge	V 40.V I 0.A	16	22	nC
$Q_{gs}$	Gate to Source Gate Charge	$V_{DD} = -10 \text{ V}, I_{D} = -6 \text{ A}$ $V_{GS} = -4.5 \text{ V}$	1.6		nC
$Q_{gd}$	Gate to Drain "Miller" Charge	v GS = -4.5 v	4		nC

### **Drain-Source Diode Characteristics**

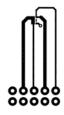
$V_{SD}$	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -1.6 \text{ A}$ (Note 2)		-0.6	-1.2	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>F</sub> = -6 A, di/dt = 100 A/μs		38	61	ns
Q <sub>rr</sub>	Reverse Recovery Charge	I <sub>F</sub> = -6 A, αι/αι = 100 A/μS		16	29	nC

#### Notes:

<sup>1.</sup> R<sub>BJA</sub> is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>BJC</sub> is guaranteed by design while R<sub>BCA</sub> is determined by the user's board design.



 a. 60 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



 b. 175 °C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width <  $300\mu\text{s},$  Duty cycle < 2.0%.
- 3. The diode connected between the gate and source serves only as protection ESD. No gate overvoltage rating is implied.

## Typical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

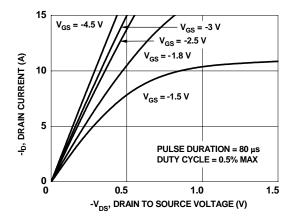


Figure 1. On Region Characteristics

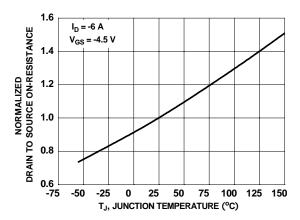


Figure 3. Normalized On Resistance vs Junction Temperature

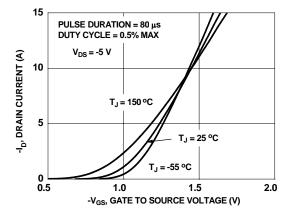


Figure 5. Transfer Characteristics

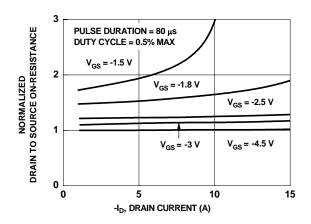


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

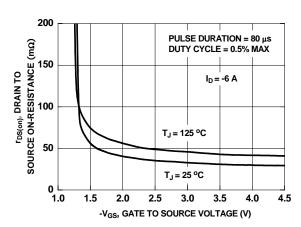


Figure 4. On-Resistance vs Gate to Source Voltage

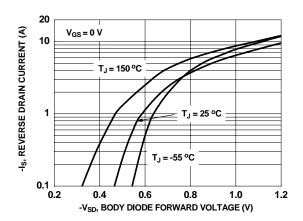


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

## **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

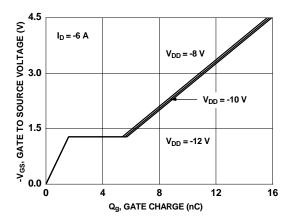


Figure 7. Gate Charge Characteristics

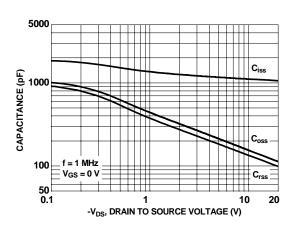


Figure 8. Capacitance vs Drain to Source Voltage

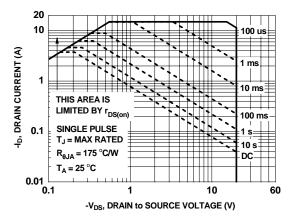


Figure 9. Forward Bias Safe Operating Area

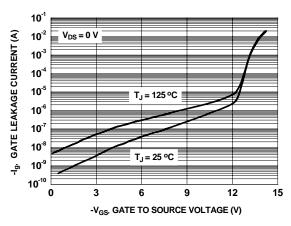


Figure 10. Gate Leakage Current vs Gate to Source Voltage

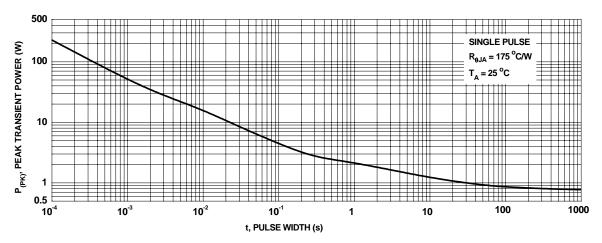


Figure 11. Single Pulse Maximum Power Dissipation

# **Typical Characteristics** T<sub>J</sub> = 25 °C unless otherwise noted

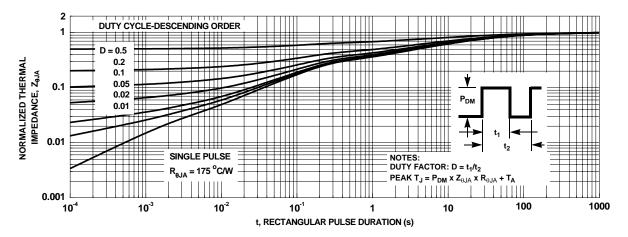
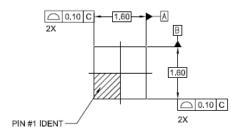
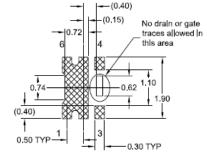


Figure 12. Junction-to-Ambient Transient Thermal Response Curve

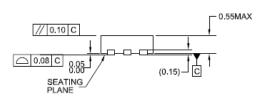
# **Dimensional Outline and Pad Layout**



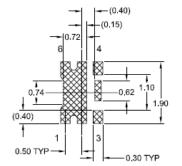
TOP VIEW



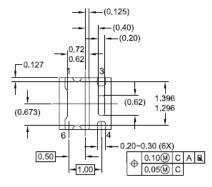
**RECOMMENDED LAND PATTERN OPT 1** 



SIDE VIEW



RECOMMENDED LAND PATTERN OPT 2



**BOTTOM VIEW** 





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